

ELECTRIC DEVICE TESTING APPARATUS

ABSTRACT OF THE DISCLOSURE

An electric device testing apparatus 10 comprises a connection terminal 51 to which an IC chip 2 to be tested is removably connected, a pusher 30 for pushing the IC chip 2 in the direction of the connection terminal 51 in order to connect the IC chip 2 to the connection terminal 51, and temperature adjusted air supply means 124, 126, 128 and 130 for blowing a temperature adjusted air to around the IC chip 2 during a test on the IC chip 2 via a through hole 110 formed on the pusher 30.

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